

Search Notes

Application/Control No.

10/617,259

Examiner

German Viana Di Prisco

Applicant(s)/Patent under
Reexamination

NA ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	252	9/14/2007	GV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	9/14/2007	GV
Inventor name and Assignee search in PALM ExPO and EAST	9/14/2007	GV
EPO Database(http://ep.espacenet.com)	9/14/2007	GV
KIPO Database (http://www.kipo.go.kr)	9/14/2007	GV
Consulted with Ken Vanderpuye and Steven Nguyen		
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